

P29FCT52AT/BT/CT P29FCT53AT/BT/CT OCTAL REGISTERED TRANSCEIVER

★ FEATURES

- Function, Pinout and Drive Compatible with the FCT, F and AM2952/53 Logic
- FCT-C speed at 6.3ns max. (Com'l)
FCT-B speed at 7.5ns max. (Com'l)
- Reduced V_{OH} (typically = 3.3V) versions of Equivalent FCT functions
- Edge-rate Control Circuitry for Significantly Improved Noise Characteristics
- ESD protection exceeds 2000V
- Power-off disable feature
- Matched Rise and Fall times
- Fully Compatible with TTL Input and Output Logic Levels
- 64 mA Sink Current (Com'l), 48 mA (Mil)
15 mA Source Current (Com'l), 12 mA (Mil)
- Manufactured In 0.7 micron PACE Technology™

★ DESCRIPTION

The P29FCT52T and P29FCT53T have two 8-bit back-to-back registers that store data flowing in both directions between two bidirectional buses. Separate clock, clock enable and 3-state output enable signals are provided for each register. Both A outputs and B outputs are guaranteed to sink 64mA.

The P29FCT52T is a non-inverting option of the P29FCT53T.

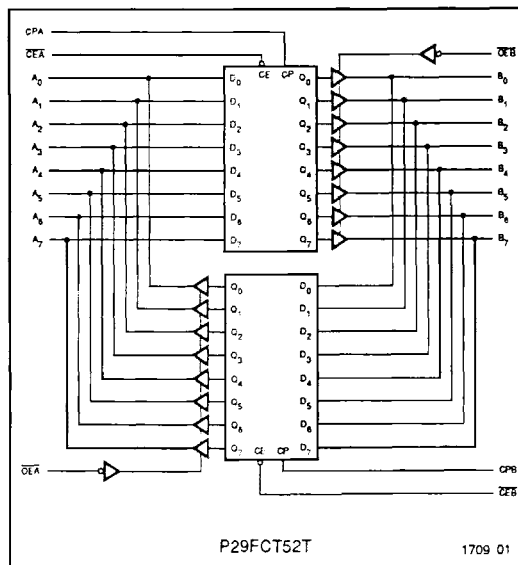
The P29FCT52T and P29FCT53T are manufactured using

PACE Technology™ which is Performance Advanced CMOS Engineered to use 0.7 micron effective channel lengths resulting in 400 picoseconds loaded* internal gate delays. PACE Technology includes two-level metal and epitaxial substrates. In addition to very high performance and very high density, the technology features latch-up protection and single event upset protection, and is supported by a Class 1 environment volume production facility.

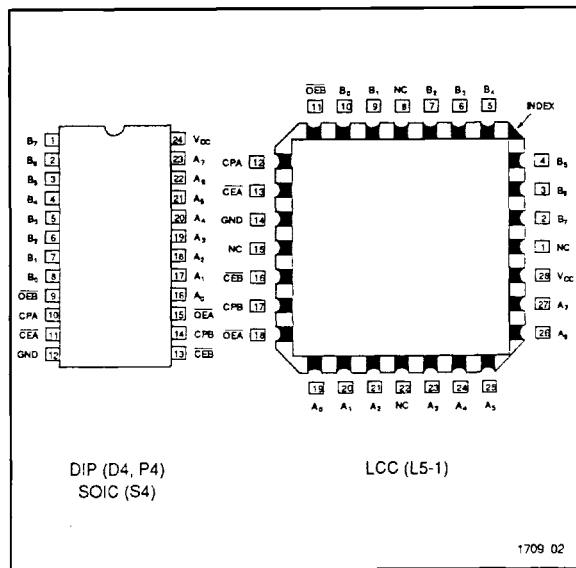
* For a fan-in/fan-out of 4 at 85°C junction temperature and 5.0 V supply. For a fan-in/fan-out of 1, the internal gate delay is 200 picosecond at room temperature.

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

★ FUNCTIONAL BLOCK DIAGRAM



PIN CONFIGURATIONS



REGISTERED FUNCTION TABLE

Inputs			Internal Q	Function
D	CP	\overline{CE}		
X	X	H	NC	Hold Data
L		L	L	Load Data
H		L	H	

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OUTPUT CONTROL

\overline{OE}	Internal Q	Y-Outputs		Function
		P29FCT52T	P29FCT53T	
H	X	Z	Z	Disable Outputs
L	L	L	H	Enable Outputs
L	H	H	L	

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PIN DESCRIPTION

Name	I/O	Description
A ₀₋₇	I/O	Eight bidirectional lines carrying the A Register inputs or B Register outputs.
B ₀₋₇	I/O	Eight bidirectional lines carrying the B Register inputs or A Register outputs.
CPA	I	Clock for the A Register. When \overline{CEA} is LOW, data is entered into the A Register on the LOW-to-HIGH transition of the CPA signal.
\overline{CEA}	I	Clock Enable for the A Register. When \overline{CEA} is LOW, data is entered into the A Register on the LOW-to-HIGH transition of the CPA signal. When \overline{CEA} is HIGH, the A Register holds its contents regardless of CPA signal transitions.
\overline{OEB}	I	Output Enable for the A Register. When \overline{OEB} is LOW, the A Register outputs are enabled onto the B ₀₋₇ lines. When \overline{OEB} is HIGH, the B ₀₋₇ outputs are in the high impedance state.
CPB	I	Clock for the B Register. When \overline{CEB} is LOW, data is entered into the B Register on the LOW-to-HIGH transition of the CPB signal.
\overline{CEB}	I	Clock Enable for the B Register. When \overline{CEB} is LOW, data is entered into the B Register on the LOW-to-HIGH transition of the CPB signal. When \overline{CEB} is HIGH, the B Register holds its contents regardless of CPB signal transitions.
\overline{OEA}	I	Output Enable for the B Register. When \overline{OEA} is LOW, the B Register outputs are enabled onto the A ₀₋₇ lines. When \overline{OEA} is HIGH, the A ₀₋₇ outputs are in the high impedance state.

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ABSOLUTE MAXIMUM RATINGS^{1,2}

Symbol	Parameter	Value	Unit
T_{STG}	Storage Temperature	-65 to +150	°C
T_A	Ambient Temperature Under Bias	-65 to +135	°C
V_{CC}	V_{CC} Potential to Ground	-0.5 to +7.0	V
P_T	Power Dissipation	0.5	W

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Notes:

- Operation beyond the limits set forth in the above table may impair the useful life of the device. Unless otherwise noted, these limits are over the operating free-air temperature range.

Symbol	Parameter	Value	Unit
I_{OUTPUT}	Current Applied to Output	120	mA
V_{IN}	Input Voltage	-0.5 to +7.0	V
V_{OUT}	Voltage Applied to Output	-0.5 to +7.0	V

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- Unused inputs must always be connected to an appropriate logic voltage level, preferably either V_{CC} or ground.

RECOMMENDED OPERATING CONDITIONS

Free Air Ambient Temperature	Min	Max
Military	-55°C	+125°C
Commercial	0°C	+70°C

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Supply Voltage (V_{CC})	Min	Max
Military	+4.5V	+5.5V
Commercial	+4.75V	+5.25V

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DC ELECTRICAL CHARACTERISTICS (Over recommended operating conditions)

Symbol	Parameter	Min	Typ ¹	Max	Units	V_{CC}	Conditions
V_{IH}	Input HIGH Voltage	2.0			V		
V_{IL}	Input LOW Voltage			0.8	V		
V_H	Hysteresis ³		0.2		V		All inputs
V_{IK}	Input Clamp Diode Voltage		-0.7	-1.2	V	MIN	$I_{IN} = -18mA$
V_{OH}	Output HIGH Voltage	Military	2.4	3.3	V	MIN	$I_{OH} = -12mA$
		Commercial	2.4	3.3	V	MIN	$I_{OH} = -15mA$
V_{OL}	Output LOW Voltage	Military	0.3	0.55	V	MIN	$I_{OL} = 48mA$
		Commercial	0.3	0.55	V	MIN	$I_{OL} = 64mA$
I_I	Input HIGH Current			20	μA	MAX	$V_{IN} = V_{CC}$
I_{IH}	Input HIGH Current (Except I/O Pins)			5	μA	MAX	$V_{IN} = 2.7V$
I_{IL}	Input LOW Current (Except I/O Pins)			-5	μA	MAX	$V_{IN} = 0.5V$
I_{IH}	Input HIGH Current (I/O Pins only)			15	μA	MAX	$V_{OUT} = 2.7V$
I_{IL}	Input LOW Current (I/O Pins only)			-15	μA	MAX	$V_{OUT} = 0.5V$
I_{OS}	Output Short Circuit Current ²	-60	-120	-225	mA	MAX	$V_{OUT} = 0.0V$
I_{OFF}	Power-off Disable			100	μA	0V	$V_{OUT} = 4.5V$
C_{IN}	Input Capacitance ³		5	10	pF	MAX	All inputs
C_{IO}	I/O Capacitance ³		9	12	pF	MAX	All outputs
I_{CC}	Quiescent Power Supply Current		0.2	1.5	mA	MAX	$V_{IN} \leq 0.2V$, $V_{IN} \geq V_{CC} - 0.2V$

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Notes:

- Typical limits are at $V_{CC} = 5.0V$, $T_A = +25^\circ C$ ambient.
- Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect

operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

- This parameter is guaranteed but not tested.

DC CHARACTERISTICS (Over recommended operating conditions unless otherwise specified.)

Symbol	Parameter	Typ ¹	Max	Units	Conditions
ΔI_{CC}	Quiescent Power Supply Current (TTL inputs)	0.5	2.0	mA	$V_{CC} = \text{MAX}$, $V_{IN} = 3.4V^2$, $f_1 = 0$, Outputs Open
I_{CCD}	Dynamic Power Supply Current ³	0.15	0.25	mA/ mHz	$V_{CC} = \text{MAX}$, One Input Toggling, 50% Duty Cycle, Outputs Open, \overline{OEA} or $\overline{OEB} = \text{GND}$, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
I_C	Total Power Supply Current ⁵	2.0	4.0	mA	$V_{CC} = \text{MAX}$, $f_0 = 10 \text{ MHz}$, 50% Duty Cycle, Outputs Open, One Bit Toggling at $f_1 = 5\text{MHz}$, \overline{OEA} or $\overline{OEB} = \text{GND}$, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
		2.5	6.0	mA	$V_{CC} = \text{MAX}$, $f_0 = 10 \text{ MHz}$, 50% Duty Cycle, Outputs Open, One Bit Toggling at $f_1 = 5\text{MHz}$, \overline{OEA} or $\overline{OEB} = \text{GND}$, $V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$
		4.3	7.8 ⁴	mA	$V_{CC} = \text{MAX}$, $f_0 = 10 \text{ MHz}$, 50% Duty Cycle, Outputs Open, Eight Bits Toggling at $f_1 = 2.5\text{MHz}$, \overline{OEA} or $\overline{OEB} = \text{GND}$, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
		6.5	16.8 ⁴	mA	$V_{CC} = \text{MAX}$, $f_0 = 10 \text{ MHz}$, 50% Duty Cycle, Outputs Open, Eight Bits Toggling at $f_1 = 2.5\text{MHz}$, \overline{OEA} or $\overline{OEB} = \text{GND}$, $V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$

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Notes:

- Typical values are at $V_{CC} = 5.0V$, +25°C ambient.
- Per TTL driven input ($V_{IN} = 3.4V$); all other inputs at V_{CC} or GND.
- This parameter is not directly testable, but is derived for use in Total Power Supply calculations.
- Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
- $I_C = I_{\text{QUIESCENT}} + I_{\text{INPUTS}} + I_{\text{DYNAMIC}}$
 $I_C = I_{CC} + \Delta I_{CC} D_H N_I + I_{CCD} (f_0/2 + f_1 N_I)$
 I_{CC} = Quiescent Current with CMOS input levels
 ΔI_{CC} = Power Supply Current for a TTL High Input ($V_{IN} = 3.4V$)

- D_H = Duty Cycle for TTL Inputs High
 - N_I = Number of TTL Inputs at D_H
 - I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)
 - f_0 = Clock Frequency for Register Devices (Zero for Non-Register Devices)
 - f_1 = Input Frequency
 - N_I = Number of Inputs at f_1
- All currents are in milliamps and all frequencies are in megahertz.

AC CHARACTERISTICS

Symbol	Parameter	P29FCT52AT/53AT				P29FCT52BT/53BT				P29FCT52CT/53CT				Units	Fig. No.
		MIL		COM'L		MIL		COM'L		MIL		COM'L			
		Min. ¹	Max.	Min. ¹	Max.	Min. ¹	Max.	Min. ¹	Max.	Min. ¹	Max.	Min. ¹	Max.		
t_{PLH} t_{PHL}	Propagation Delay CPA, CPB to B_n , A_n	2.0	11.0	2.0	10.0	2.0	8.0	2.0	7.5	2.0	7.3	2.0	6.3	ns	1,5
t_{PZH} t_{PZL}	Output Enable Time OEA or OEB to A_n or B_n	1.5	13.0	1.5	10.5	1.5	8.5	1.5	8.0	1.5	8.0	1.5	7.0	ns	1,7,8
t_{PHZ} t_{PLZ}	Output Enable Time OEA or OEB to A_n or B_n	1.5	10.0	1.5	10.0	1.5	8.0	1.5	7.5	1.5	7.5	1.5	6.5	ns	1,7,8

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Notes:

1. Minimum limits are guaranteed but not tested on Propagation Delays.
2. AC Characteristics guaranteed with $C_L = 50pF$ as shown in Figure 1.

AC OPERATING REQUIREMENTS

Symbol	Parameter	P29FCT52AT/53AT				P29FCT52BT/53BT				P29FCT52CT/53CT				Units	Fig. No.
		MIL		COM'L		MIL		COM'L		MIL		COM'L			
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
$t_s(H)$ $t_s(L)$	Setup Time, HIGH or LOW, A_n , B_n to CPA, CPB	2.5	—	2.5	—	2.5	—	2.5	—	2.5	—	2.5	—	ns	4
$t_h(H)$ $t_h(L)$	Hold Time, HIGH or LOW, A_n , B_n to CPA, CPB	2.0	—	2.0	—	1.5	—	1.5	—	1.5	—	1.5	—	ns	4
$t_s(H)$ $t_s(L)$	Set-up Time, HIGH or LOW, \overline{CEA} , \overline{CEB} to CPA, CPB	3.0	—	3.0	—	3.0	—	3.0	—	3.0	—	3.0	—	ns	4
$t_h(H)$ $t_h(L)$	Hold Time, HIGH or LOW, \overline{CEA} , \overline{CEB} to CPA, CPB	2.0	—	2.0	—	2.0	—	2.0	—	2.0	—	2.0	—	ns	4
$t_w(H)$ $t_w(L)$	Pulse Width, HIGH ³ or LOW, CPA or CPB	3.0	—	3.0	—	3.0	—	3.0	—	3.0	—	3.0	—	ns	5

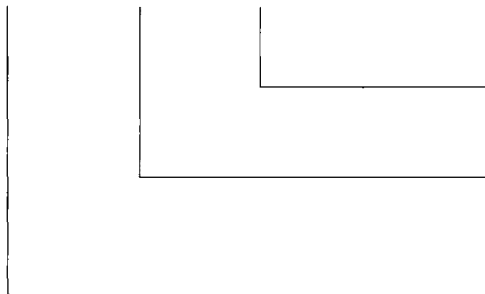
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Note:

3. This parameter is guaranteed but not tested

ORDERING INFORMATION

P29FCTxxx
Device x x
 Package Processing



Blank Commercial
M Military Temperature
B MIL-STD-883, Class B

P Plastic DIP
D CERDIP
SO Small Outline IC
L Leadless Chip Carrier

52AT Non-inverting Octal Registered Transceiver
53AT Inverting Octal Registered Transceiver
52BT Fast Non-inverting Octal Registered Transceiver
53BT Fast Inverting Octal Registered Transceiver
52CT Ultra Fast Non-inverting Octal Registered Transceiver
53CT Ultra Fast Inverting Octal Registered Transceiver



